

CS152
Computer Architecture and Engineering
Lecture 4

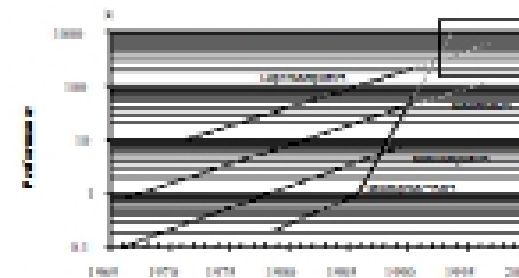
Cost and Design

September 12, 2001

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lecture slides: <http://www-inst.eecs.berkeley.edu/~cs152/>

Review: Performance and Technology Trends



Technology Power: $1.2 \times 1.2 \times 1.2 = 1.7 \times / \text{year}$

- Feature Size: shrinks 10% / yr. \Rightarrow Switching speed improves 1.2 / yr.
- Density: Improves 1.2x / yr.
- Die Area: 1.2x / yr.

RISC lesson is to keep the ISA as simple as possible:

- Shorter design cycle \Rightarrow fully exploit the advancing technology (~3yr)
- Advanced branch prediction and pipeline techniques
- Bigger and more sophisticated on-chip caches

Review: Characterize a Gate

- Input capacitance for each input
- For each input-to-output path:
 - For each output transition type (H \rightarrow L, L \rightarrow H, H \rightarrow Z, L \rightarrow Z ... etc.)
 - Internal delay (ns)
 - Load dependent delay (ns / fF)
- Example: 2-input NAND Gate

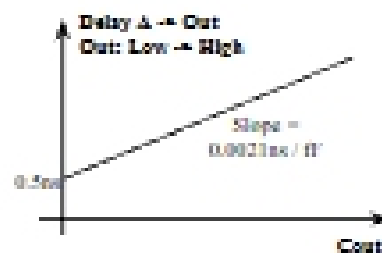


For A and B: Input Load (I.L.) = 61 fF

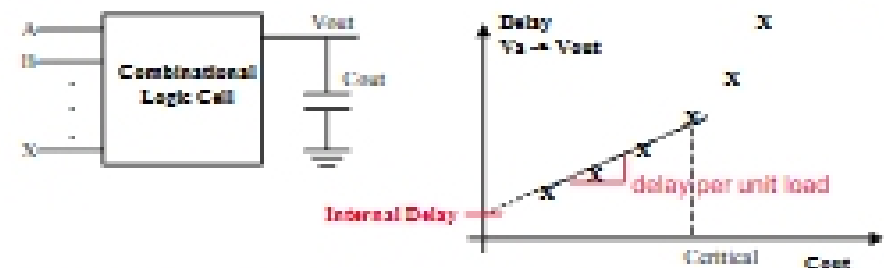
For either A \rightarrow Out or B \rightarrow Out:

$T_{HL} = 0.5 \text{ ns}$ $T_{LH} = 0.002 \text{ ns / fF}$

$T_{HL} = 0.1 \text{ ns}$ $T_{LH} = 0.002 \text{ ns / fF}$



Review: General C/L Cell Delay Model

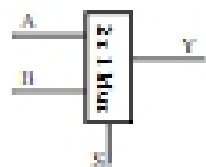


Combinational Cell (symbol) is fully specified by:

- functional (input \rightarrow output) behavior
 - truth-table, logic equation, VHDL
- load factor of each input
- critical propagation delay from each input to each output for each transition
 - $T_{iL}(A, \alpha) = \text{Fixed Internal Delay} + \text{Load-dependent-delay} \times \text{load}$

Linear model composes

Review: More complicated gates



Three Components:

- Input Load
- Load Dependent Delay
- Internal Delays
 - One for each input path → output transition

Input Load: $A = 61 \text{ fF}$, $B = 61 \text{ fF}$, $S = 111 \text{ fF}$

Load Dependent Delay:

- $T_{AY|hf} = 0.0021 \text{ ns / fF}$ $T_{AY|hl} = 0.0020 \text{ ns / fF}$
- $T_{BY|hf} = 0.0021 \text{ ns / fF}$ $T_{BY|hl} = 0.0020 \text{ ns / fF}$
- $T_{SY|hf} = 0.0021 \text{ ns / fF}$ $T_{SY|hl} = 0.0020 \text{ ns / fF}$

Internal Delay:

- $T_{AY|h} = 0.844 \text{ ns}$ $T_{BY|h} = 0.844 \text{ ns}$
- Fun Exercise: $T_{AY|h}$, $T_{BY|h}$, $T_{SY|h}$, $T_{SY|l}$

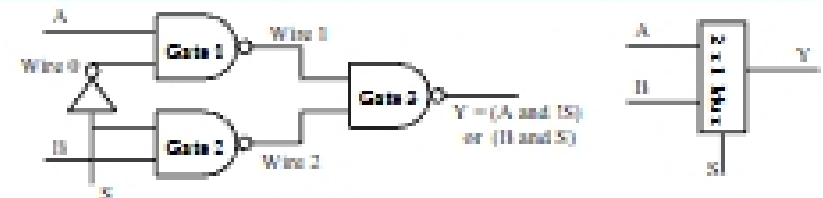
How do we compute these numbers?

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2 to 1 MUX: Input Load and Load Dependent Delay



Input Load (I.L.)

- A, B: I.L. (NAND) = 61 fF
- S: I.L. (INV) + I.L. (NAND) = $50 \text{ fF} + 61 \text{ fF} = 111 \text{ fF}$

Load Dependent Delay (L.D.D.): Same as Gate 3

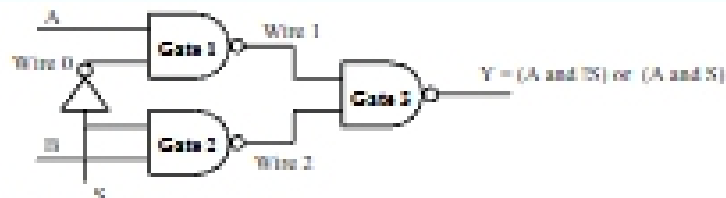
- $T_{AY|hf} = 0.0021 \text{ ns / fF}$ $T_{AY|hl} = 0.0020 \text{ ns / fF}$
- $T_{BY|hf} = 0.0021 \text{ ns / fF}$ $T_{BY|hl} = 0.0020 \text{ ns / fF}$
- $T_{SY|hf} = 0.0021 \text{ ns / fF}$ $T_{SY|hl} = 0.0020 \text{ ns / fF}$

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2 to 1 MUX: Internal Delay Calculation



Internal Delay (I.D.):

- A to Y: I.D. $G1 + (\text{Wire 1 } C + G3 \text{ Input } C) + \text{L.D.D. } G1 + \text{I.D. } G3$
- B to Y: I.D. $G2 + (\text{Wire 2 } C + G3 \text{ Input } C) + \text{L.D.D. } G2 + \text{I.D. } G3$
- S to Y (Worst Case): I.D. $\text{Inv} + (\text{Wire 0 } C + G1 \text{ Input } C) + \text{L.D.D. } \text{Inv} + \text{Internal Delay A to Y}$

We can approximate the effect of "Wire 1 C" by:

- Assume Wire 1 has the same C as all the gate C attached to it.

Specific Example:

- $T_{AY|h} = \text{TPHl } G1 + (2.0 * 61 \text{ fF}) * \text{TPHf } G1 + \text{TPHl } G3$
 $= 0.1 \text{ ns} + 122 \text{ fF} * 0.0020 \text{ ns/fF} + 0.6 \text{ ns} = 0.844 \text{ ns}$

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CS152 Logic Elements

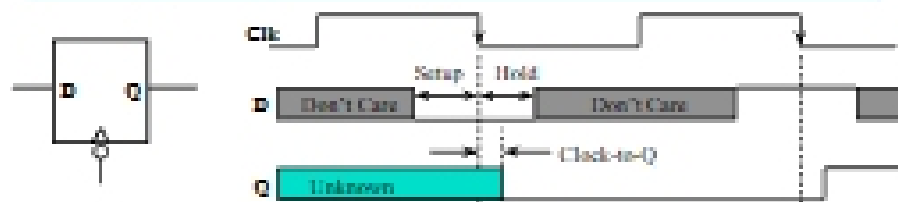
- NAND2, NAND3, NAND4
- NOR2, NOR3, NOR4
- INV1x (normal inverter)
- INV4x (inverter with large output drive)
- XOR2
- XNOR2
- PWR: source of 1's
- GND: source of 0's
- fast MUXes
- D flip flop with negative edge triggered

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Storage Element's Timing Model



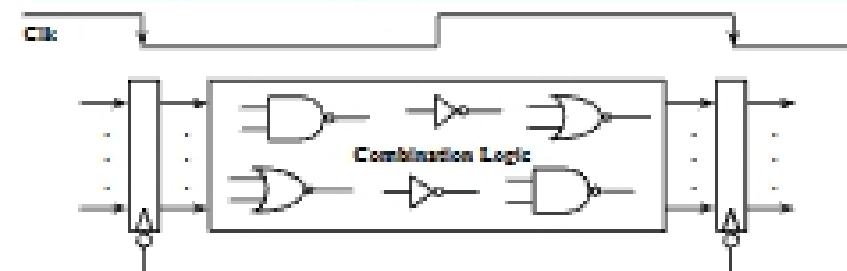
- **Setup Time:** Input must be stable BEFORE the trigger clock edge
- **Hold Time:** Input must REMAIN stable after the trigger clock edge
- **Clock-to-Q time:**
 - Output cannot change instantaneously at the trigger clock edge
 - Similar to delay in logic gates, two components:
 - Internal Clock-to-Q
 - Load dependent Clock-to-Q
- **Typical for class: 1ns Setup, 0.5ns Hold**

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Clocking Methodology



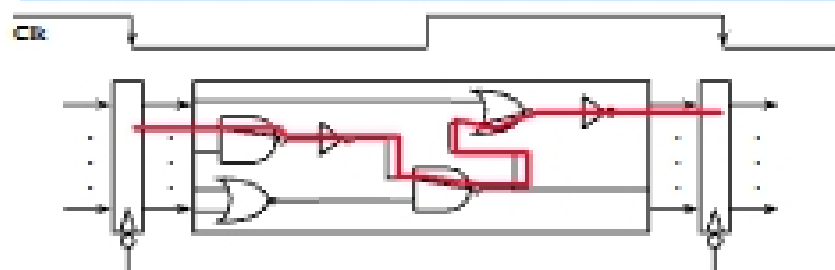
- All storage elements are clocked by the same clock edge
- The combination logic block's:
 - Inputs are updated at each clock tick
 - All outputs MUST be stable before the next clock tick

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Critical Path & Cycle Time



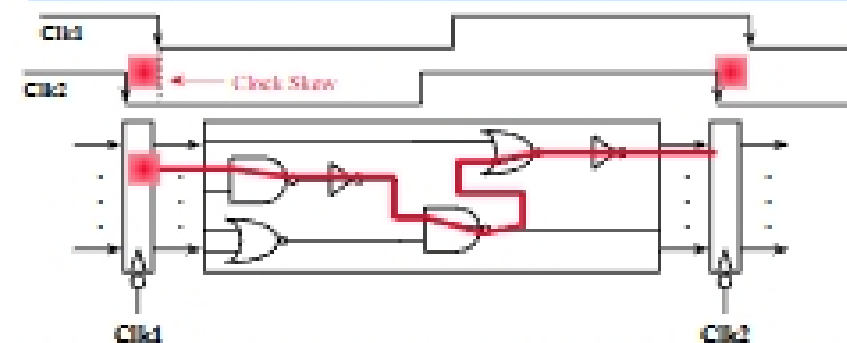
- **Critical path:** the slowest path between any two storage devices
- Cycle time is a function of the critical path
- must be greater than:
 - Clock-to-Q + Longest Path through Combination Logic + Setup

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Clock Skew's Effect on Cycle Time



- The worst case scenario for cycle time consideration:
 - The input register sees CLK1
 - The output register sees CLK2
- **Cycle Time - Clock Skew ≥ CLK-to-Q + Longest Delay + Setup**
 \Rightarrow **Cycle Time ≥ CLK-to-Q + Longest Delay + Setup + Clock Skew**

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